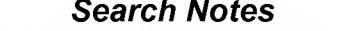


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/584,624	NAKANO ET AL.
	Examiner	Art Unit
	TAN Q. NGUYEN	3661

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner